AN INTEGRATED CRACK-OPENING METHOD FOR DETERMINING THE WORK OF FRACTURE **OF BONDED POLYMER INTERFACES**

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This is a simple, non-destructive test of bond toughness that can be used for process development and monitoring. It can be applied to any bonding process that does not introduce major plastic deformation of microstructures at the interface – including plasma- or UV/ozoneactivated bonding.



embossed recesses in the present experiments shows that for $p_0 = 20$ MPa, and assuming E = 1.6 GPa, the contact pressure lies between 17.5 and 19.9 MPa in the region in which crack tips finally reside:

- dip or bonded 1 day after the HCI dip gave crack lengths that generally reached 1 mm within a few hours.

activation treatments.

Detail: polymer mechanical properties

The test method requires an assumption of linear elasticity, which, for a thermoplastic, would break down if bonding and/or unloading was performed too close to the softening temperature of the material. If the time of propagation of the crack were comparable with the relaxation time-constant of the material, our estimate of bond toughness would be an overestimate because a portion of the elastic potential energy released from the material would be unavailable for crack enlargement.

A detailed model of the visco-elastic-plastic behavior of PMMA [8], in combination with analytical results for crack propagation in viscoelastic media [9], lead us to believe that for unloading at 40 C, as in these experiments, an assumption of linear elasticity is valid for at least the first few minutes after unloading. The extent of the subsequent apparent weakening of the bonds may in fact be underestimated because the polymer has relaxed. Analysis of the size of any such error is needed.



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